



Machine Vision and Machine Learning in Interdisciplinary Research

Guest Editor:

Message from the Guest Editor

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Deadline for manuscript
submissions:

20 October 2024

- **Industry 4.0 and Manufacturing Applications:** Here, we invite papers that discuss the integration of MV&ML in industrial automation, quality control, predictive maintenance, and supply chain optimization.
- **Technological Innovations in Machine Vision and Machine Learning:** This theme will focus on the latest advancements in algorithms, techniques, and methodologies in MV&ML. Papers may cover areas such as deep learning, neural networks, pattern recognition, and image processing, emphasizing their novel application or theoretical innovation.
- **Healthcare and Life Sciences:** We welcome studies demonstrating novel applications in medical imaging, predictive analytics, and BCI analysis.
- **Environmental Monitoring and Smart Cities:** This theme seeks research that applies MV&ML to environmental challenges and enhancing urban living, such as climate change analysis, wildlife monitoring, pollution tracking, infrastructure monitoring, and showcasing how these technologies contribute to smarter, more efficient cities.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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